

IEEE Waveform Generation Measurement and Analysis Technical Committee (TC10)
Meeting Agenda
18 October 2022 / 11:00 AM – 1:00 PM (EDT)

1. Call to Order
2. Introductions and Roll Call
3. Approval of the Agenda
4. Approval of the minutes from the previous meeting
5. TC10 business
 - a. eTools – questions, comments, concerns
 - b. Quarter meetings – notifications, invitations
 - c. New standards
6. Working Groups Updates
 - a. Revision of IEE Std 181, IEEE Standard for Transitions, Pulses, and Related Waveforms
 - i. Lead: Nick Paulter
 - b. Revision of IEEE Std 1241, IEEE Standard for Terminology and Test Methods for Analog-to-Digital Converters
 - i. Lead: Nick Paulter
 - c. Revision of IEEE Std 1658, IEEE Standard for Terminology and Test Methods of Digital-to-Analog Converter Devices
 - i. Lead: Luca DeVito
 - d. Revision of IEEE Std 1696, IEEE Standard for Terminology and Test Methods for Circuit Probes
 - i. Lead: John Jendzurski
7. Guest presentation
 - a. John Calvin (see next page)
8. Adjourn

Information on guest presentation

Title of presentation:

Instrument noise compensation in higher order modulated signals

John Calvin
Keysight Technologies

Presenter biography: John is a Senior Internet Infrastructure and IP Wireline Solutions Product Planner with Keysight Technologies. John manages instrument and solution definitions that address new and emerging needs for both software and instrumentation in the Datacenter field.

Abstract: With the rapid evolution of high-speed networking, the evolution of 100Gbps/lane to 200Gbps/lane is evolving on a highly compressed time scale. The need to effectively manage the test instrumentation noise contributions in measurements has become increasingly complex with lower input referred noise limits and higher order modulation schemes such as PAM4 (4 level pulse amplitude modulation). This presentation will outline a progressive method of random noise and jitter compensation on contemporary real time oscilloscopes.